

**Search Notes**

Application/Control No.

10/665,440

Examiner

Dah-Wei D. Yuan

Applicant(s)/Patent under  
Reexamination

SKINLO, DAVID M.

Art Unit

1745

**SEARCHED**

Class	Subclass	Date	Examiner
429	12,34,46	11/13/2006	DWY
29	623.1	11/13/2006	DWY

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	11/13/2006	DWY